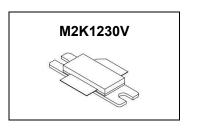
300W, 0.96-1.2GHz 50V High Power RF LDMOS

Description

The M2K1230V is a 300W single ended 50V LDMOS, internally matched for any applications within 0.96-1.215GHz

It is suitable for use in avionics application especially high duty cycle or wide pulse It supports any modulated signal at either saturated or linear application.



Typical performance(on 960-1215MHz application board with devices soldered)

V_{DS}=50V,Idq=100mA, Pulsed CW, 50% duty cycle, 10us pulse width

Freq	P1dB	P1dB	P1dB	P1dB	P3dB	P3dB	P3dB
(MHz)	(dBm)	(W)	Eff(%)	Gain(dB)	(dBm)	(W)	Eff(%)
960	54.99	315.8	54.9	18.22	55.65	367.1	57.5
1030	54.98	315.0	58.8	18.47	55.58	361.6	60.8
1090	54.89	308.4	59.8	18.43	55.51	355.4	61.6
1130	54.84	304.9	60.6	19.46	55.39	345.9	61.5
1170	54.75	298.5	59.4	18.69	55.27	336.5	60.2
1215	54.56	286.0	57.0	19.59	55.12	325.5	57.9

Features

- High Efficiency and Linear Gain Operations
- Integrated ESD Protection
- Excellent thermal stability, low HCI drift
- Large Positive and Negative Gate/Source Voltage Range for Improved Class C Operation
- Pb-free, RoHS-compliant

Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
DrainSource Voltage	V _{DSS}	+115	Vdc
GateSource Voltage	V _{GS}	-10 to +10	Vdc
Operating Voltage	V_{DD}	+55	Vdc
Storage Temperature Range	Tstg	-65 to +150	°C
Case Operating Temperature	Tc	+150	°C
Operating Junction Temperature	T٦	+225	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value	Unit
Thermal Resistance, Junction to Case			
Pulse: Case Temperature 75 C, 300 W Peak, 10usec Pulse Width,	RθJC	0.2	°C/W
10% Duty Cycle, 50 Vdc, 1030 MHz			

Table 3. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JESD22A114)	Class 2

Table 4. Electrical Characteristics (T_A = 25 °C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
	,		, ,		

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DC Characteristics

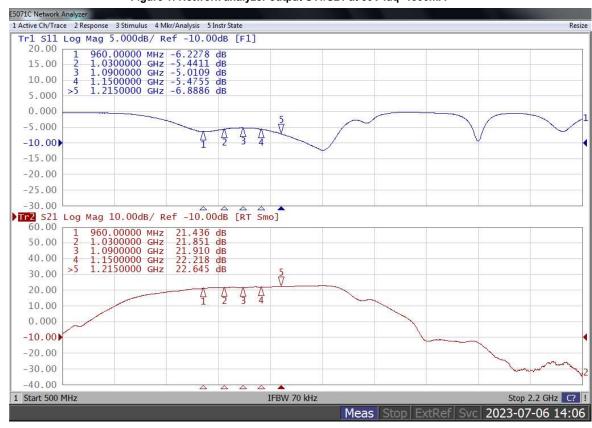
Drain-Source Breakdown Voltage	Vpss	110			V	
(V _{GS} =0V; I _D =100uA)	V DSS	110			V	
Zero Gate Voltage Drain Leakage Current				10		
$(V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V})$	I _{DSS}			10	μΑ	
GateSource Leakage Current				1		
$(V_{GS} = 6 \text{ V}, V_{DS} = 0 \text{ V})$	I _{GSS}			Į.	μА	
Gate Threshold Voltage	\/ (4b)		1.6		V	
$(V_{DS} = 50V, I_{D} = 600 \text{ uA})$	V _{GS} (th)		1.0		V	
Gate Quiescent Voltage	V		3.1		V	
(V _{DD} = 50 V, I _{DQ} = 100 mA, Measured in Functional Test)	$V_{GS(Q)}$		3.1		V	

Load Mismatch (In Innogration Test Fixture, 50 ohm system): $V_{DD} = 50 \text{ Vdc}$, $I_{DQ} = 100 \text{mA}$, f = 1030 MHz, pulse width:10us, duty cycle:10%, Pout=300W

VSWR: > 7:1 at All Phase Angles	No Device Degradation
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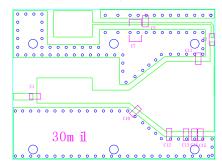
TYPICAL CHARACTERISTICS

Figure 1: Network analyzer output S11/S21 at 50V ldq=1500mA



M2K1230V LDMOS TRANSISTOR

Reference Circuit of Test Fixture Assembly Diagram (Layout file upon request, 30mil RO4350)



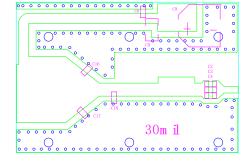


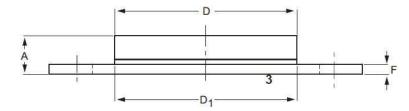
Table 5. Test Circuit Component Designations and Values

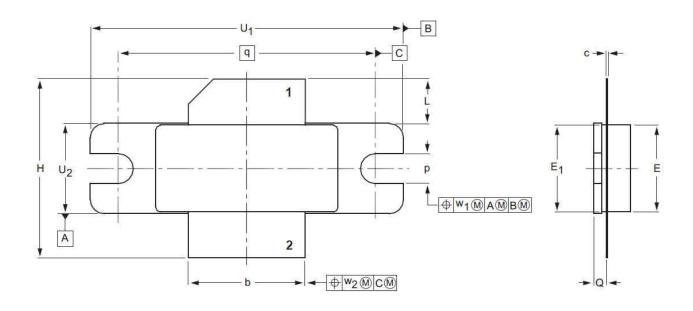
Designator	Comment	Footprint	Quantity
C1,	47pF/250V	0805	1
C2, C3, C4	20 pF/250V	0805	3
C5, C6	47pF/250V	0805/1210	2
C7, C8	10uF/100V	1210	2
C9	100uF/63V		1
C10, C13, C15, C16,	2 2 5 7 2 5 0 1	0805	5
C17	3.3pF/250V		5
C11	6.8pF/250V	0805	1
C12, C14	4.7pF/250V	0805	2
C18	2.2pF/250V	0805	1
R1	10 Ω	0603	1

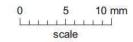
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Package Outline

Flanged ceramic package; 2 mounting holes; 2 leads (1—DRAIN、2—GATE、3—SOURCE)







UNIT	A	b	С	D	D ₁	E	E ₁	F	н	L	р	Ø	q	U1	U ₂	W ₁	W ₂
	4.72	12.83	0.15	20.02	19.96	9.50	9.53	1.14	19.94	5.33	3.38	1.70	27.04	34.16	9.91	0.25	0.54
mm	3.43	12.57	0.08	19.61	19.66	9.30	9.25	0.89	18.92	4.32	3.12	1.45	27.94 33.91	33.91	9.65	0.51	
inches	0.186	0.505	0.006	0.788	0.786	0.374	0.375	0.045	0.785	0.210	0.133	0.067	1.100	1.345	0.390	0.01	0.02
inches	0.135	0.495	0.003	0.772	0.774	0.366	0.364	0.035	0.745	0.170	0.123	0.057	1.100	1.335	0.380	0.01	0.02

OUTLINE		REFERENCE		EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	IOOOL DATE
PKG-B2E					03/12/2013

M2K1230V LDMOS TRANSISTOR

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Revision history

Table 5. Document revision history

Date	Revision	Datasheet Status
2023/7/7	Rev 1.0	Preliminary datasheet

Application data based on LSM-23-22

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